

International **IR** Rectifier

PD - 95500

IRFP054VPbF

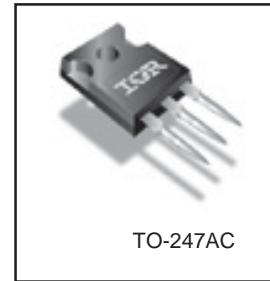
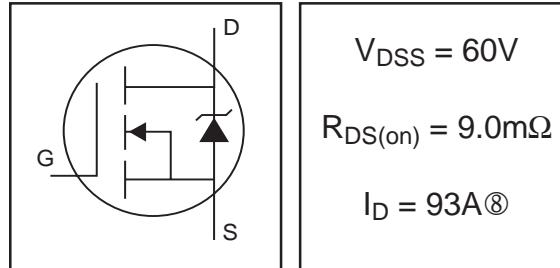
HEXFET® Power MOSFET

- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Optimized for SMPS Applications
- Lead-Free

Description

Advanced HEXFET® Power MOSFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-247 package is preferred for commercial-industrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because of its isolated mounting hole.



Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	93 ^⑧	
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	66	
I_{DM}	Pulsed Drain Current ①⑦	360	
$P_D @ T_C = 25^\circ C$	Power Dissipation	180	W
	Linear Derating Factor	1.2	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
I_{AR}	Avalanche Current①	90	A
E_{AR}	Repetitive Avalanche Energy①	18	mJ
dv/dt	Peak Diode Recovery dv/dt ③⑦	4.7	V/ns
T_J	Operating Junction and	-55 to + 175	°C
T_{STG}	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

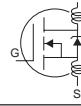
Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	—	0.85	
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.24	—	°C/W
$R_{\theta JA}$	Junction-to-Ambient	—	40	

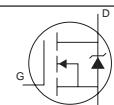
IRFP054VPbF

International
Rectifier

Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	60	—	—	V	$V_{\text{GS}} = 0\text{V}$, $I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}/\Delta T_J}$	Breakdown Voltage Temp. Coefficient	—	0.066	—	V°C	Reference to 25°C , $I_D = 1\text{mA}$
$R_{\text{DS}(\text{on})}$	Static Drain-to-Source On-Resistance	—	—	9.0	$\text{m}\Omega$	$V_{\text{GS}} = 10\text{V}$, $I_D = 54\text{A}$ ④⑦
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	2.0	—	4.0	V	$V_{\text{DS}} = V_{\text{GS}}$, $I_D = 250\mu\text{A}$
g_{fs}	Forward Transconductance	61	—	—	S	$V_{\text{DS}} = 25\text{V}$, $I_D = 54\text{A}$ ④⑦
I_{DSS}	Drain-to-Source Leakage Current	—	—	25	μA	$V_{\text{DS}} = 60\text{V}$, $V_{\text{GS}} = 0\text{V}$
		—	—	250		$V_{\text{DS}} = 48\text{V}$, $V_{\text{GS}} = 0\text{V}$, $T_J = 150^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{\text{GS}} = 20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{\text{GS}} = -20\text{V}$
Q_g	Total Gate Charge	—	—	170	nC	$I_D = 64\text{A}$
Q_{gs}	Gate-to-Source Charge	—	—	39		$V_{\text{DS}} = 48\text{V}$
Q_{gd}	Gate-to-Drain ("Miller") Charge	—	—	59		$V_{\text{GS}} = 10\text{V}$, See Fig. 6 and 13⑦
$t_{\text{d}(\text{on})}$	Turn-On Delay Time	—	22	—	ns	$V_{\text{DD}} = 30\text{V}$
t_r	Rise Time	—	160	—		$I_D = 64\text{A}$
$t_{\text{d}(\text{off})}$	Turn-Off Delay Time	—	77	—		$R_G = 6.2\Omega$
t_f	Fall Time	—	110	—		$V_{\text{GS}} = 10\text{V}$, See Fig. 10 ④⑦
L_D	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact
L_S	Internal Source Inductance	—	7.5	—		
C_{iss}	Input Capacitance	—	4080	—	pF	$V_{\text{GS}} = 0\text{V}$
C_{oss}	Output Capacitance	—	840	—		$V_{\text{DS}} = 25\text{V}$
C_{rss}	Reverse Transfer Capacitance	—	180	—		$f = 1.0\text{MHz}$, See Fig. 5⑦
E_{AS}	Single Pulse Avalanche Energy②	—	1080③	220⑥	mJ	$I_{\text{AS}} = 90\text{A}$, $L = 54\mu\text{H}$ ⑦

Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	93⑧	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode)①	—	—	360		
V_{SD}	Diode Forward Voltage	—	—	1.2	V	$T_J = 25^\circ\text{C}$, $I_S = 90\text{A}$, $V_{\text{GS}} = 0\text{V}$ ④⑦
t_{rr}	Reverse Recovery Time	—	78	120	ns	$T_J = 25^\circ\text{C}$, $I_F = 64\text{A}$
Q_{rr}	Reverse Recovery Charge	—	250	380	nC	$dI/dt = 100\text{A}/\mu\text{s}$ ④⑦
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L_S+L_D)				

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② Starting $T_J = 25^\circ\text{C}$, $L = 54\mu\text{H}$
 $R_G = 25\Omega$, $I_{\text{AS}} = 90\text{A}$, $V_{\text{GS}}=10\text{V}$ (See Figure 12)
- ③ $I_{\text{SD}} \leq 90\text{A}$, $di/dt \leq 250\text{A}/\mu\text{s}$, $V_{\text{DD}} \leq V_{(\text{BR})\text{DSS}}$, $T_J \leq 175^\circ\text{C}$
- ④ Pulse width $\leq 400\mu\text{s}$; duty cycle $\leq 2\%$.
- ⑤ This is a typical value at device destruction and represents operation outside rated limits.
- ⑥ This is a calculated value limited to $T_J = 175^\circ\text{C}$.
- ⑦ This is tested with same test conditions as the existing data sheet
- ⑧ Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 90A.

IRFP054VPbF

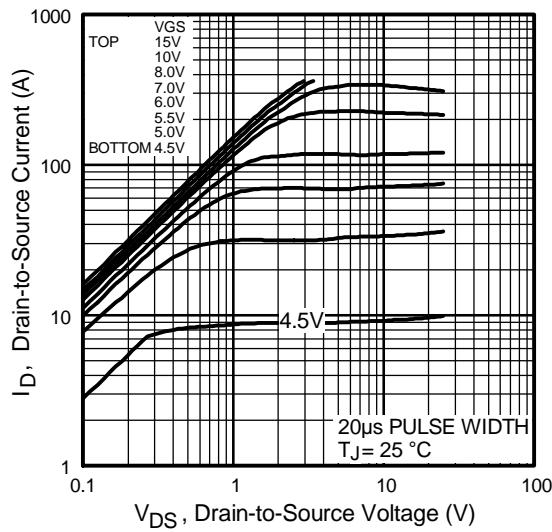


Fig 1. Typical Output Characteristics

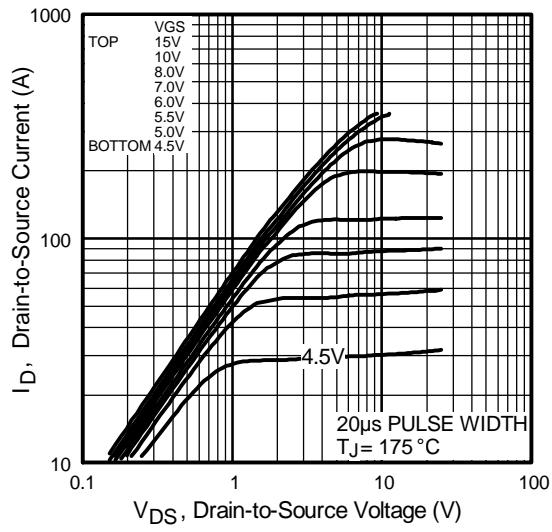


Fig 2. Typical Output Characteristics

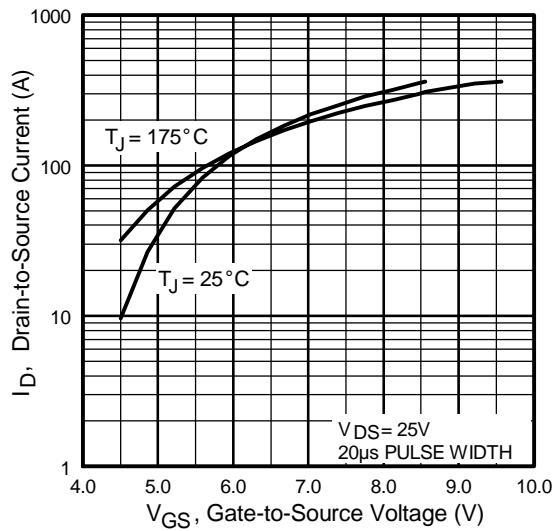


Fig 3. Typical Transfer Characteristics

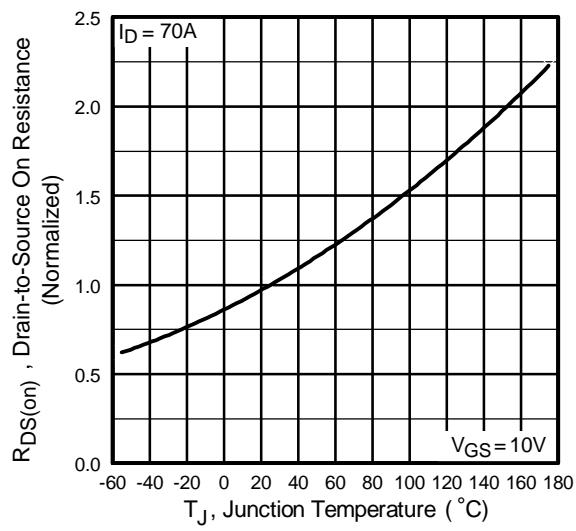


Fig 4. Normalized On-Resistance
Vs. Temperature

IRFP054VPbF

International
Rectifier

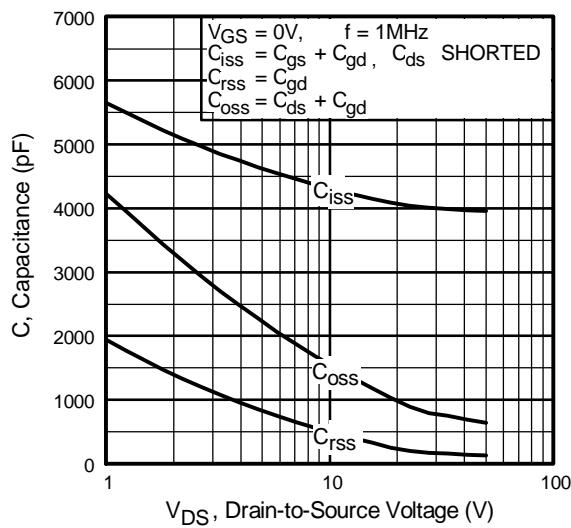


Fig 5. Typical Capacitance Vs.
Drain-to-Source Voltage

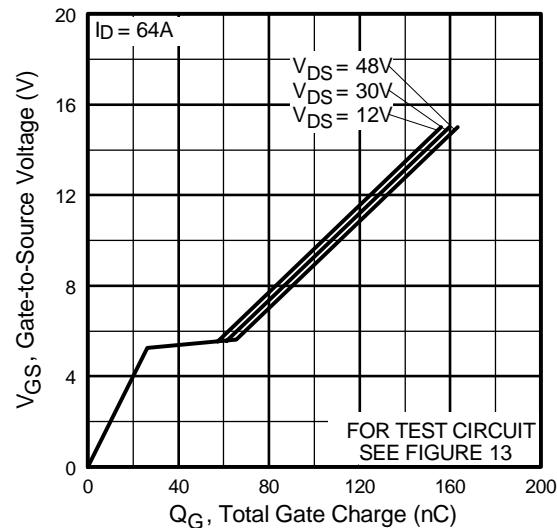


Fig 6. Typical Gate Charge Vs.
Gate-to-Source Voltage

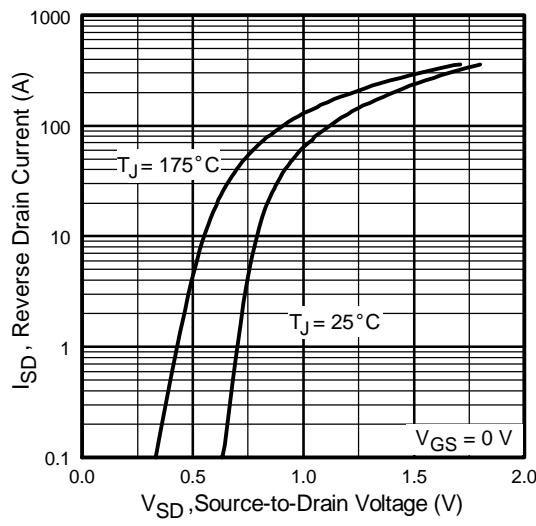


Fig 7. Typical Source-Drain Diode
Forward Voltage

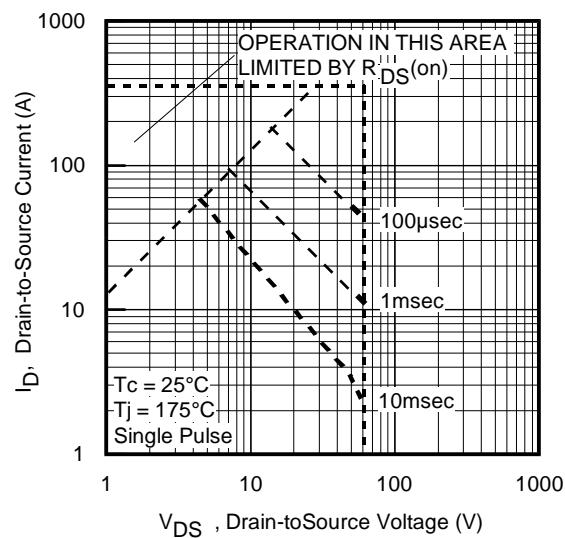


Fig 8. Maximum Safe Operating Area

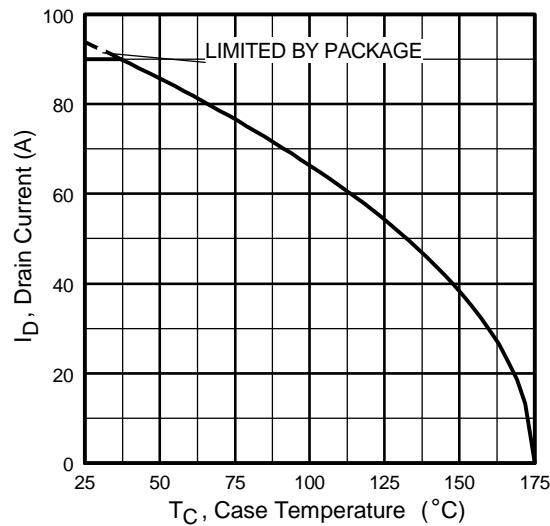


Fig 9. Maximum Drain Current Vs.
Case Temperature

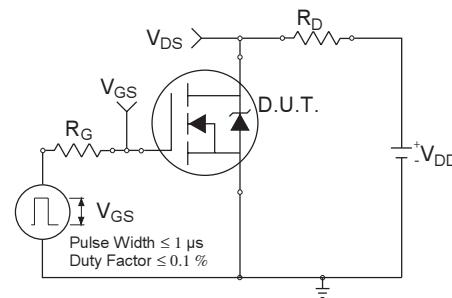


Fig 10a. Switching Time Test Circuit

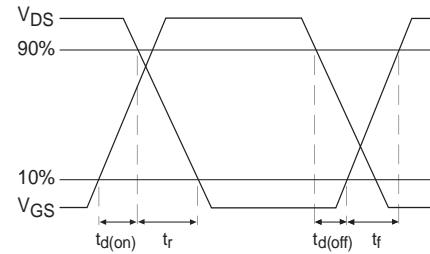


Fig 10b. Switching Time Waveforms

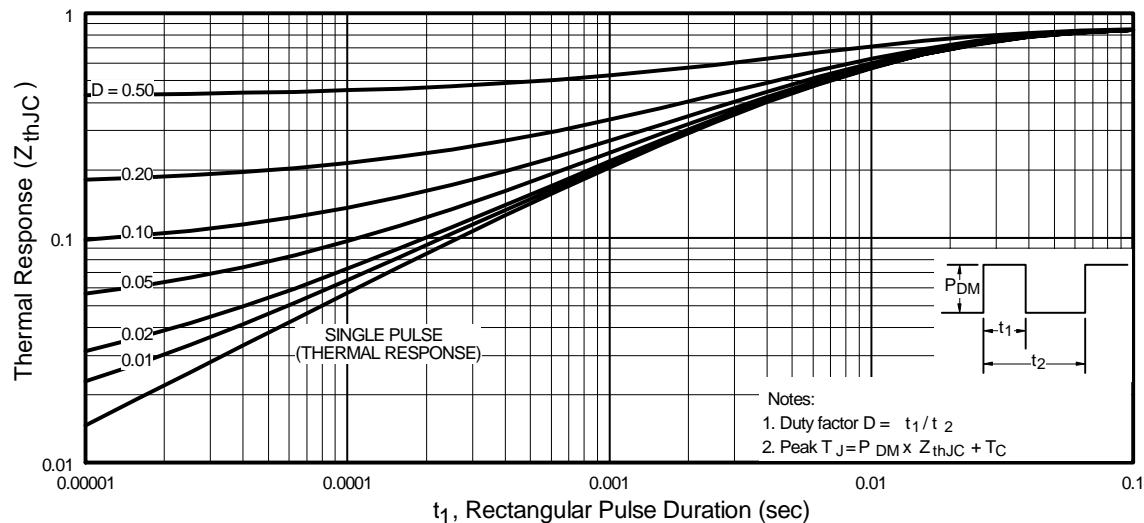


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

IRFP054VPbF

International
Rectifier

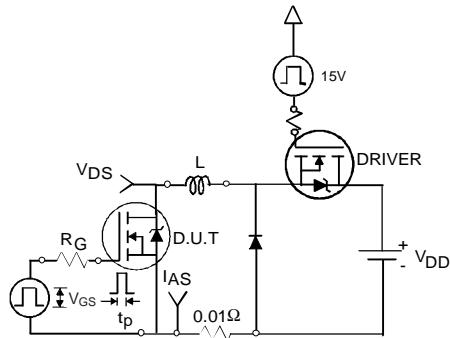


Fig 12a. Unclamped Inductive Test Circuit

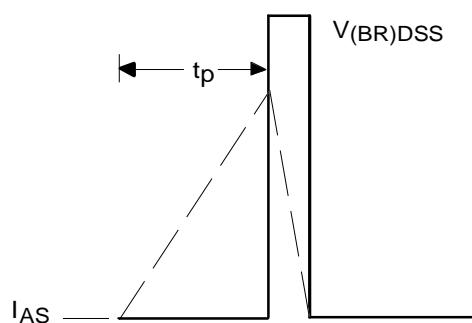


Fig 12b. Unclamped Inductive Waveforms

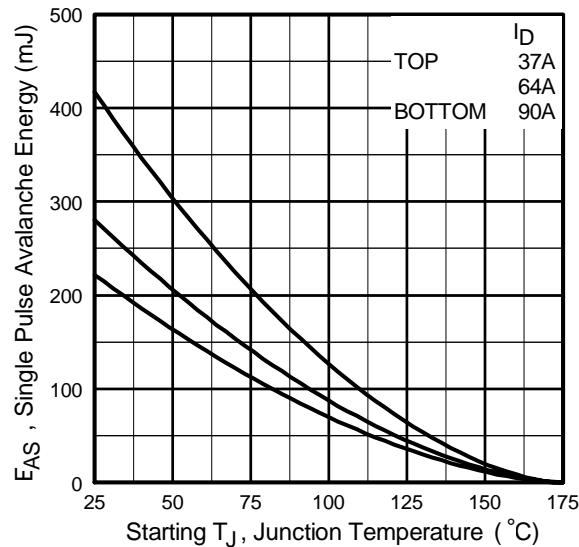


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

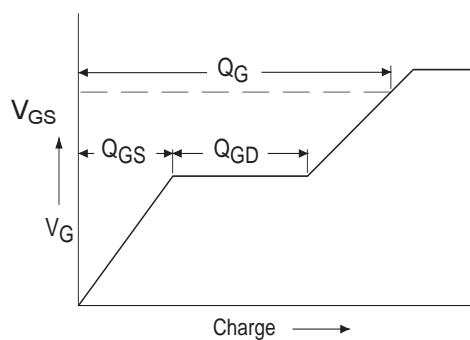


Fig 13a. Basic Gate Charge Waveform

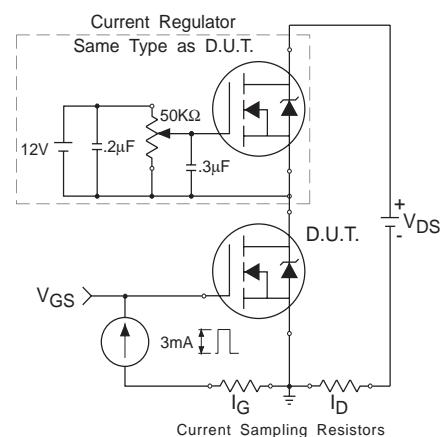
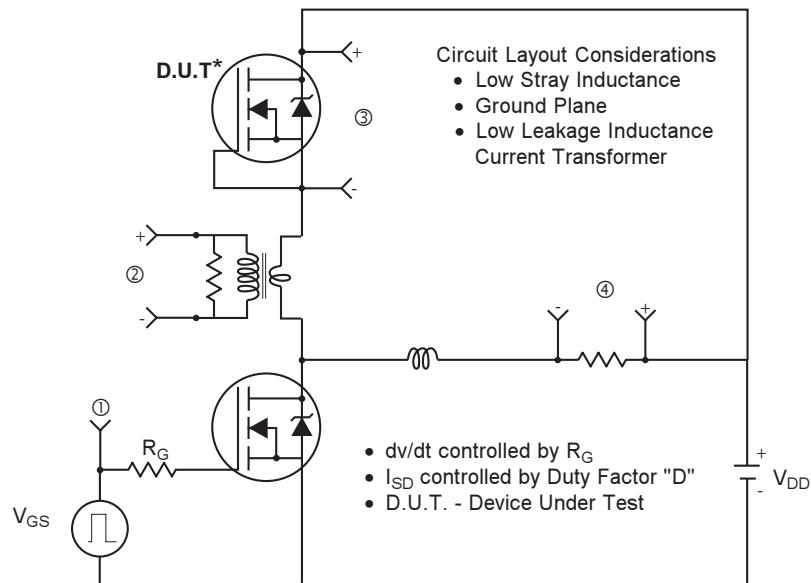
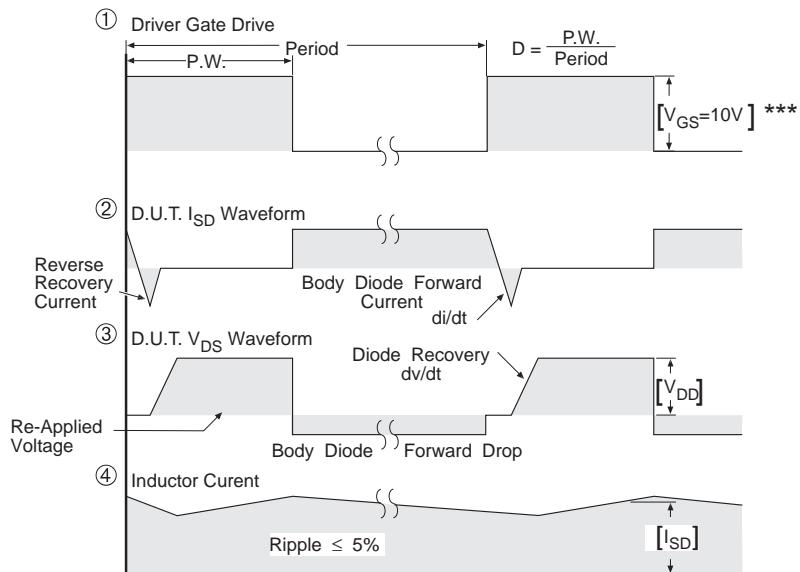


Fig 13b. Gate Charge Test Circuit

Peak Diode Recovery dv/dt Test Circuit



* Reverse Polarity of D.U.T for P-Channel



*** $V_{GS} = 5.0\text{V}$ for Logic Level and 3V Drive Devices

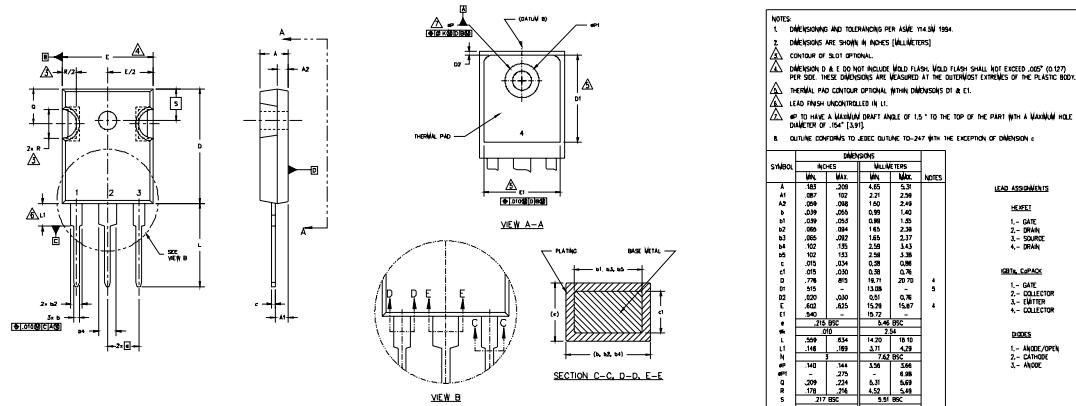
Fig 14. For N-channel HEXFET® power MOSFETs

IRFP054VPbF

International
IR Rectifier

TO-247AC Package Outline

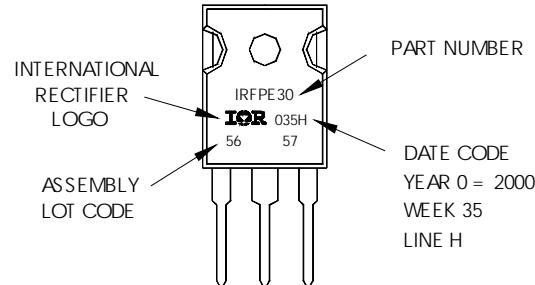
Dimensions are shown in millimeters (inches)



TO-247AC Part Marking Information

EXAMPLE: THIS IS AN IRFPE30
WTH ASSEMBLY
LOT CODE 5657
ASSEMBLED ON WW 35, 2000
IN THE ASSEMBLY LINE "H"

Note: "P" in assembly line position indicates "Lead-Free"



Data and specifications subject to change without notice.
This product has been designed and qualified for the Automotive [Q101] market.
Qualification Standards can be found on IR's Web site.

International
IR Rectifier

IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105
TAC Fax: (310) 252-7903

Visit us at www.irf.com for sales contact information. 07/04

www.irf.com

Note: For the most current drawings please refer to the IR website at:
<http://www.irf.com/package/>